

**Notice of References Cited**

Application/Control No.

09/824,900

Applicant(s)/Patent Under  
Reexamination  
ABBOTT ET AL.

Examiner

Tam V Nguyen

Art Unit

2172

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0147880 A1	10-2002	WANG BALDONADO, MICHELLE Q.	711/1
	B	US-6,363,377	03-2002	Kravets et al.	707/4
	C	US-6,263,317	07-2001	Sharp et al.	705/26
	D	US-6,490,579 B1	12-2002	Gao et al.	707/4
	E	US-6,442,549 B1	08-2002	Schneider, Eric	707/10
	F	US-6,405,206 B1	06-2002	Kayahara, Naoki	707/102
	G	US-6542889B1	04-2003	Aggarwal et al.	707/5
	H	US-6282517B1	08-2001	Wolfe et al.	705/26
	I	US-6272507B1	08-2001	Pirolli et al.	707/513
	J	US-6549915B2	04-2003	Abbott, III et al.	707/104.1
	K	US-6169976B1	01-2001	Colosso	705/59
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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